

<b>Notice of References Cited</b>	Application/Control No. 10/667,730	Applicant(s)/Patent Under Reexamination SCHMIDT ET AL.	
	Examiner Andy Huynh	Art Unit 2818	Page 1 of 1

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	M	US-			

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**NON-PATENT DOCUMENTS**

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*	U	Fiederling, R. et al.: "Injection and Detection of a Spin-Polarized Current in a Light-Emitting Diode", Nature, Vol. 402, December 16, 1999, pp. 787-790
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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